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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

(Case No. 219.003-US)

in <del>the</del> A	Sollaa	ation	of:	Yam	ada

Serial No: 09/865,528

Group

Filed: May 29, 2001

Art Unit: 2829

**Before** 

Title: Semiconductor Device Test Method and

**Semiconductor Device Tester** 

Examiner: V. Nguyen

Commissioner for Patents

P. O. Box 1450

Alexandria, VA 22313-1450

### **FEE TRANSMITTAL**

#### Dear Sir:

Transmitted herewith is an Information Disclosure Statement (1 page + Form PTO-1449 (1 sheet) and references cited therein.

The fee has been calculated as shown below:

CLAIMS AS AMENDED						
	Claims Highest Number Extra Rate					
	Remaining	Previously Paid		Large	Small	Amount
Number of Claims In (in excess of 20)	0	0	0	\$18.00	\$9.00	-0-
Independent Claims (in excess of 3)	0	0	0	\$84.00	\$42.00	-0-
Extension Fee: a) One Month \$110.00 \$55.00					-0-	
Filing of Information Disclosure Statement (37 C.F.R. §1.17(p)):						\$180.00
TOTAL FEE DUE:						\$180.00

## **Method of Payment:**

[XX] A check payable to the Commissioner of Patents and Trademarks, in the amount of \$180.00 is enclosed as payment of the Total Fee.

1 Please charge my Deposit Acc. 50-0763 in the amount of \$ to cover the above fees. A duplicate copy of this sheet is enclosed.

[XX] The Commissioner is hereby authorized to charge any fees that may be required, or credit any overpayment to Deposit Acc. 50-0763. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

Neil Steinberg, Reg. No. 34,735 Telephone No. (650) 968-8079

Date: May 5, 2004





# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE (219.001-US)

In re Application of: YAMADA	)
Serial No: 09/451,440	)
Filed: NOVEMBER 30, 1999	)
Title: CONTACT HOLE STANDARD TEST DEVICE	)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

### Certificate of Mailing under 37 CFR 1.8

I hereby certify that the attached: **(1)** Information Disclosure Statement (1 page + Modified PTO-1449 (1 sheet) and References cited therein); **(2)** Fee Transmittal (1 page + 1 copy thereof); **(3)** Check (\$180.00) are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

on May 5, 2004.

Signature

Print Name of Person Signing Certificate



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

(Case No. 219.003-US)

Group

Before

Art Unit: 2829

Examiner: V. Nguyen

In t	the	Appl	ication	of:	Yama	da
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Serial No: 09/865,528

Filed: **May 29, 2001** 

Title: Semiconductor Device Test Method and

**Semiconductor Device Tester** 

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

### INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these documents formally of record with the initial Office Action.

Respectfully submitted,

Date: May 5, 2004

Neil A. Steinberg Reg. No. 34,735 650-968-8079

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			S. PATENT DUCUMENTS	·		
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,989,919					
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		I				

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	63-009807	1/1988	Japan			
					<u> </u>	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99/, available from <a href="http://www.fabsol.com/us/images/library/21.pdf">http://www.fabsol.com/us/images/library/21.pdf</a>

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.